

ACCELERATED TEST METHOD AND SYSTEM

Inventor: Yen-Fu LIU

Docket No. 4006-276

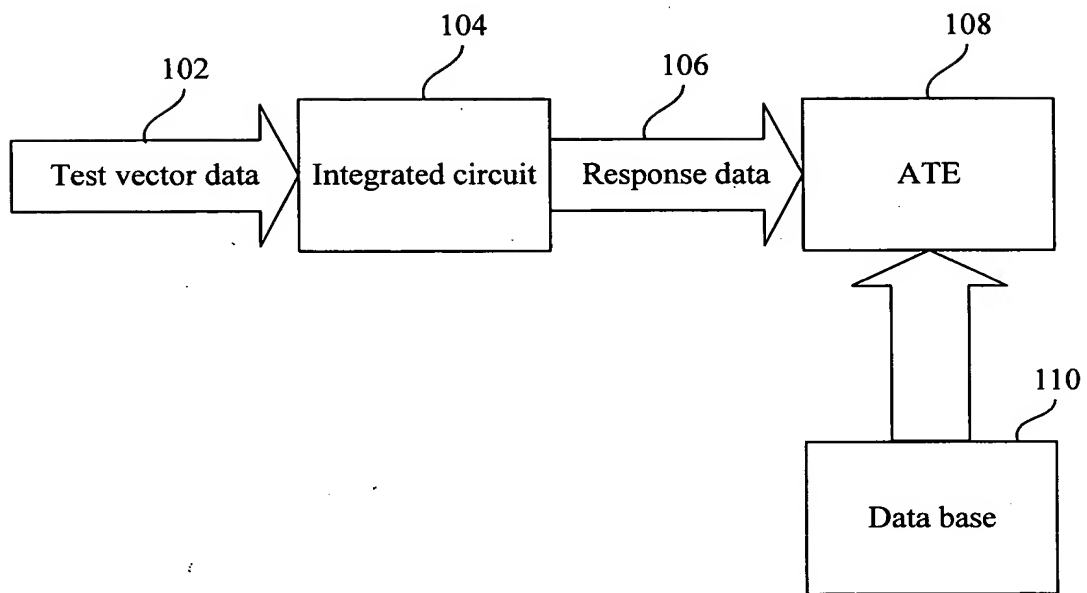


Fig. 1

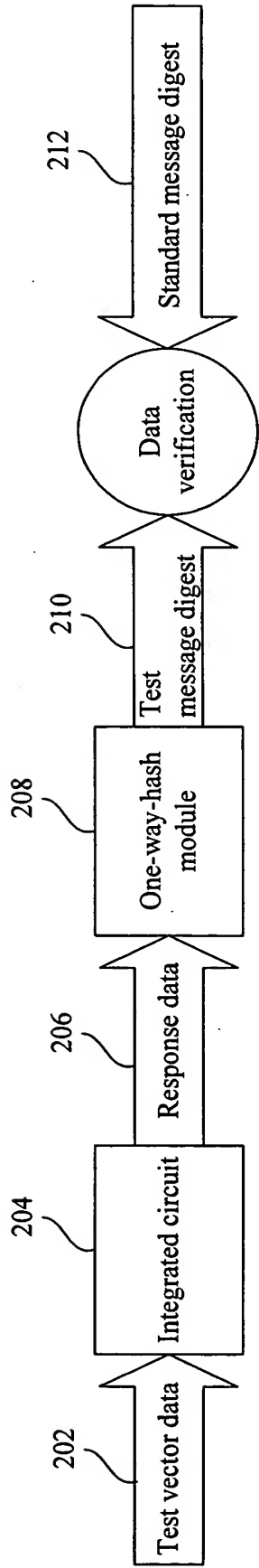


Fig. 2A

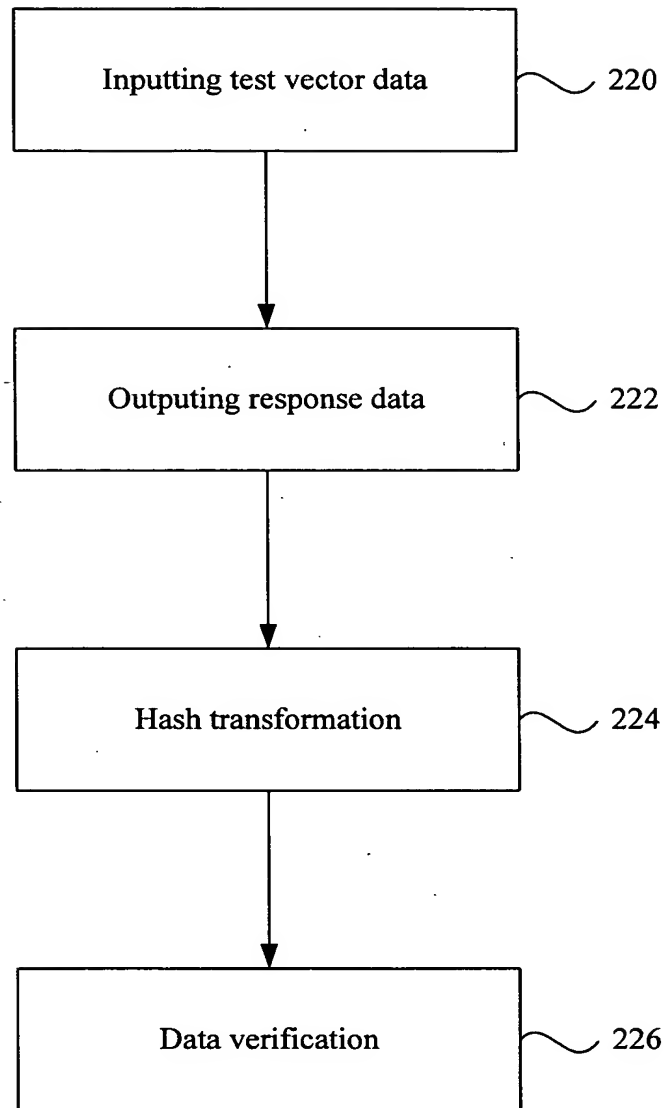


Fig. 2B

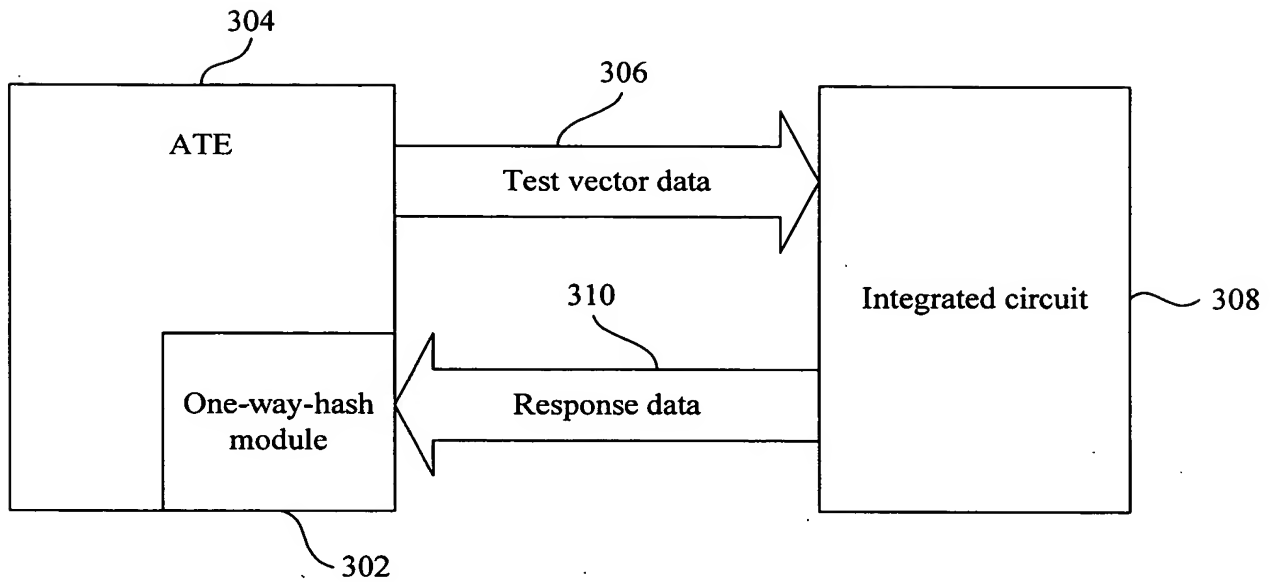


Fig. 3

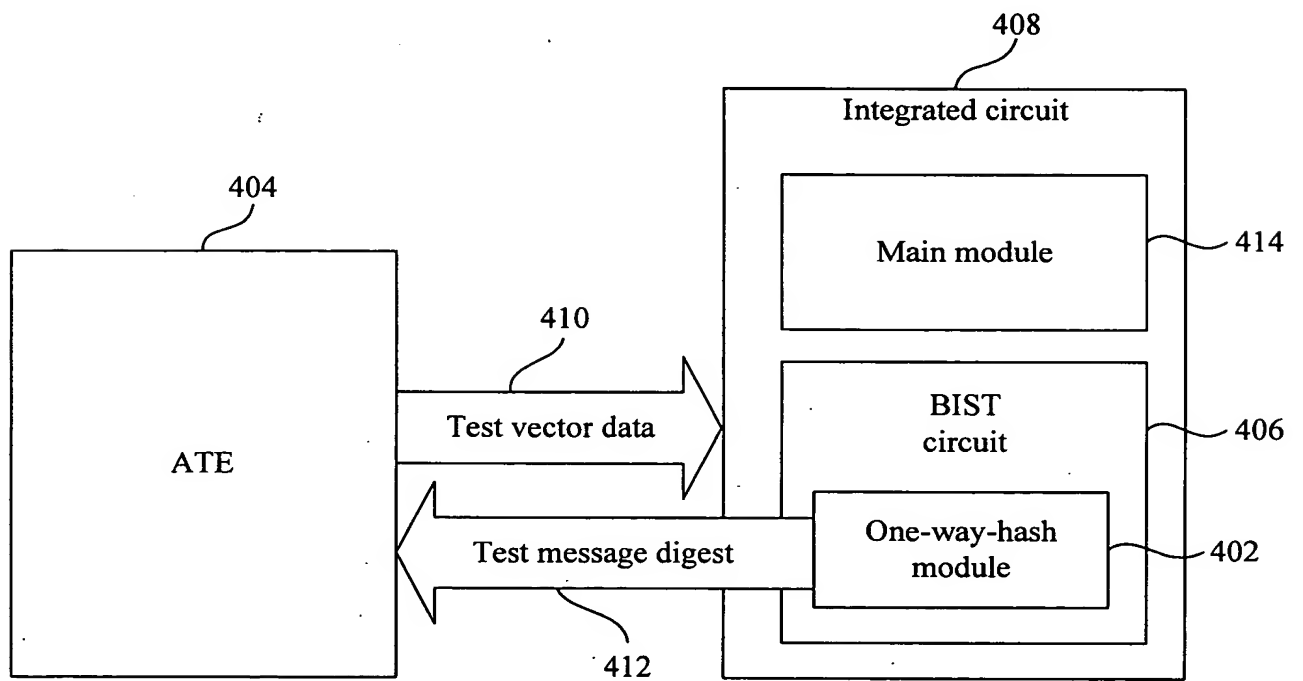


Fig. 4

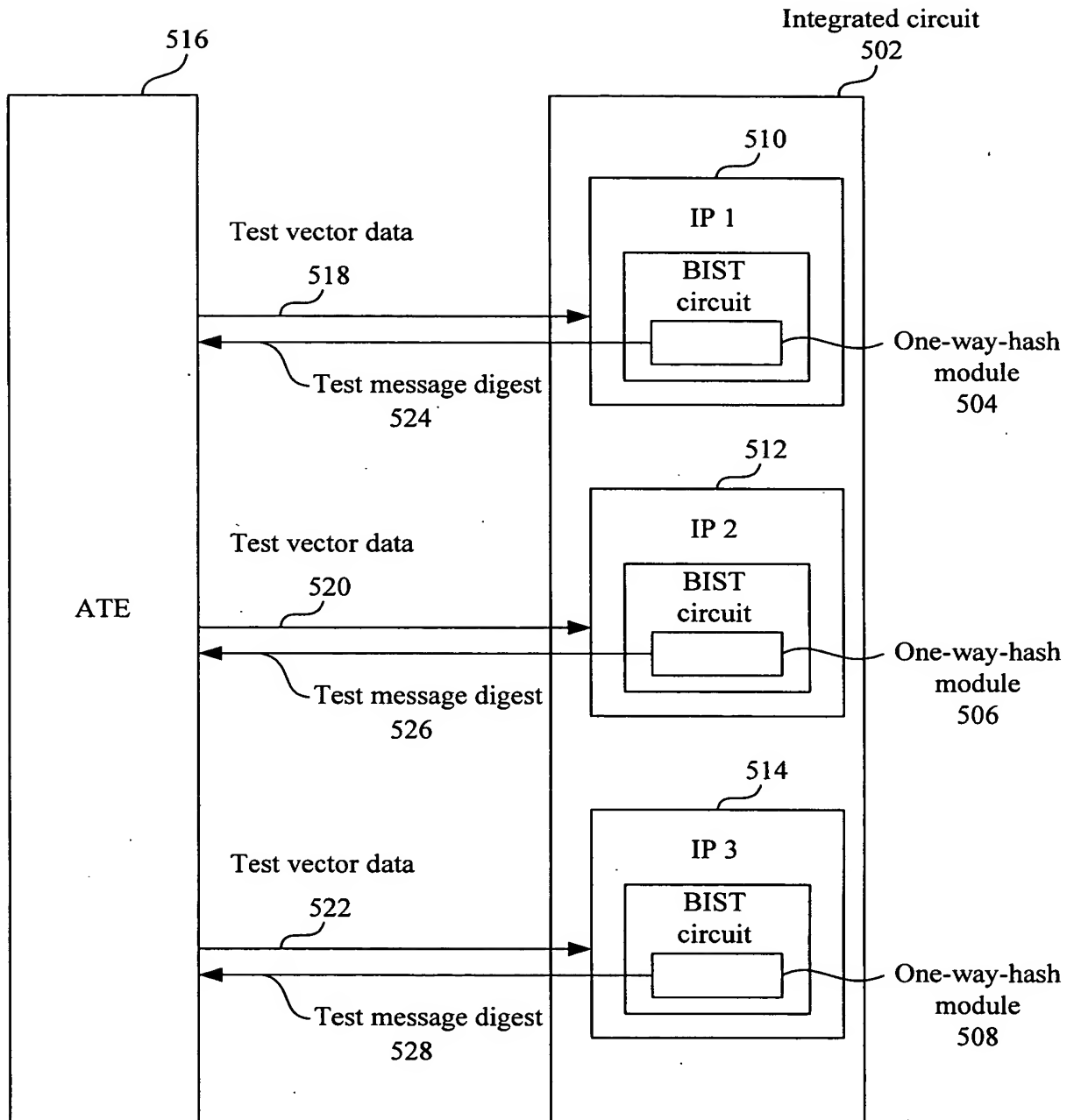


Fig. 5